

Schweizerische Eidgenossenschaft Confédération suisse Confederazione Svizzera Confederaziun svizra

Swiss Confederation

SCS Directory

Federal Department of Economic Affairs, Education and Research EAER

State Secretariat for Economic Affairs SECO Swiss Accreditation Service SAS

Accreditation number: SCS 0079

International standard:	ISO/IEC 17025:2017	
Swiss standard:	SN EN ISO/IEC 17025:2018	
Lab 1 Leica Geosystems AG Heinrich-Wild-Strasse 9435 Heerbrugg SG Switzerland	Head:	Wolfgang Hardegen
	Responsible for MS:	Hannes Juen
	Telephone:	+41 71 727 31 31
	E-Mail:	wolfgang.hardegen@leica-ge- osystems.com
Leica Geosystems AG Mönchmattweg 5 5035 Unterentfelden AG Switzerland	Internet:	http://www.leica-geosystems.com
	Initial accreditation:	02.06.1997
	Current accreditation:	16.04.2020 to 15.04.2025
	Scope of accreditation see:	www.sas.admin.ch (Accredited bodies)

Scope of accreditation as of 25.10.2021

Calibration laboratory for Length and Angle

Calibration and Measurement Capability (CMC)

Measured Quantity / Instrument or Gauge	Measurement Range	Measurement Conditions	Best Measurement Capability ± ¹⁾	Remarks	Lab
ELECTRO-OPTICAL DISTANCE MEASURING INSTRUMENTS					Lab 1
Distance (to prism)	60 m	Laboratory	0,16 mm	Measurement of linearity deviations	
	120 m		0,26 mm		
Distance (non prism)	60 m	Laboratory	0,17 mm		
	120 m		0,26 mm		
Distance (to prism)	500 m	Terrain	0,07 mm	Standard deviation of a single	



Schweizerische Eidgenossenschaft Confédération suisse Confederazione Svizzera Confederaziun svizra

Swiss Confederation

SCS Directory

Federal Department of Economic Affairs, Education and Research EAER

State Secretariat for Economic Affairs SECO Swiss Accreditation Service SAS

Accreditation number: SCS 0079

Measured Quantity / Instrument or Gauge	Measurement Range	Measurement Conditions	Best Measurement Capability ± ¹⁾	Remarks	Lab
Distance (to prism)	1000 m		0,10 mm	measurement,	
	2000 m		0,18 mm	according to	
	3000 m		0,26 mm	ISO 17123-4	
Distance (non prism)	500 m	Terrain	0,13 mm		
	1000 m		0,15 mm		
	2000 m		0,21 mm		
	3000 m		0,28 mm		
FREQUENCY	100 MHz	Temperature range	10,0 Hz	Deviation of the modulation	Lab 1
	50 MHz	-20 °C +50 °C	5,0 Hz		
	15 MHz		1,5 Hz	frequency in function of the temperature	
THEODOLITES					Lab 1
Angles	Hz full circle	Laboratory	0,08 "	Standard deviation	
	V ± 126 °		0,08 "	of a dual face	
	(Zenith angle)			Measurement according to ISO 17123-3	
LASER TRACKER INSTRUMENTS					Lab 1 Lab 2
Two-face error		1,5 m – 6 m Laboratory	6 µm	Testing method ac- cording to ISO/FDIS 10360-10:2021	
Spatial length to retro-reflector	2300 mm	1,5 m – 6 m Laboratory	9 µm	ditto	
Spatial length to retro-reflector (in- line)	1,5 m – 53 m	Laboratory	5 µm	ditto	
Probing form error on sphere (with retro-reflector, tac- tile probe and opti- cal scanning probe)	25 mm	2 m – 10 m Laboratory	8 µm	ditto	

25.10.2021 / Q dfp/dil 0079scsvz en The given extended measurement uncertainty is the standard uncertainty of the measurement multiplied by an extension factor k = 2, which corresponds to a confidence level of about 95% for a normal distribution.



Schweizerische Eidgenossenschaft Confédération suisse Confederazione Svizzera Confederaziun svizra

Swiss Confederation

SCS Directory

Federal Department of Economic Affairs, Education and Research EAER

State Secretariat for Economic Affairs SECO Swiss Accreditation Service SAS

Accreditation number: SCS 0079

Measured Quantity / Instrument or Gauge	Measurement Range	Measurement Conditions	Best Measurement Capability ± ¹⁾	Remarks	Lab
Probing size error on sphere (with retro-reflector, tac- tile probe and opti- cal scanning probe)	50 mm	2 m – 10 m Laboratory	6 µm	ditto	
Orientation error with tactile probe		2 m – 10 m Laboratory	10 µm	ditto	
Probing form error on flat (with optical scanning probe)	400 mm flat	2 m Laboratory	12 µm	ditto	
Spatial length with tactile probe	2300 mm	Laboratory	12 µm	According to instruc- tions "Customer In- formation Leica La- ser Tracker Calibration Method" (v2.0.0en 2021)	
Spatial length with optical probe (scanning)	2300 mm	Laboratory	12 µm	dito	
Scale of Interferom- eter (IFM, Wave- length)	633 nm	Laboratory	0.00002 nm (0.03 ppm)	Deviation of the wavelength from the reference	
Laser Tracker Instruments and Absolute Distance Meters					Lab 1 Lab 2
Scale of Absolute Distance Meter (Frequency)	25 MHz	Laboratory	0.75 Hz (0.03 ppm)	Deviation of the modulation fre- quency from the ref- erence	
Distance Offset of Absolute Distance Meter	6 m	Laboratory	7 µm		
Meteo Station - Temperature - Pressure - Humidity	One discrete measurement at current con- ditions	Actual laboratory condition	0.06 °C 0.7 hPa 2.5 % r.H.		

In case of contradictions in the language versions of the directories, the German version shall apply.

//*/*/*

25.10.2021 / Q dfp/dil 0079scsvz en

3/3

The given extended measurement uncertainty is the standard uncertainty of the measurement multiplied by an extension factor k = 2, which corresponds to a confidence level of about 95% for a normal distribution.